

**Attachment D: Application Form**

**Last name:** Touzel

**First name:** Jérôme

**Company:** Infineon Technologies AG, Munich



**Position within the company:** Senior Manager for Failure Analysis.

**Preferred EUFANET Board of Directors Position:** Secretary

**Candidate short resume:**

- Ph.D in electronic at the University of Montpellier in 1984.
- 17 years experience in failure analysis after ca. 5 years as process engineer for the integration of logic technologies. Manager of a FA department within the Product and Technology Analysis Group / Munich, currently in charge of failure analysis for Chip Card and Security Products after several years of FA for Memory Products. In addition, responsible for the FIB Service Group, especially regarding the circuit edits aspects.
- Speaker of the ITG-group “Failure analysis strategies” (ITG : “user group” inter-company in Germany, sub-group of the VDE)

**Vision of EUFANET’s future:**

Further consolidation of the network – especially in Germany, e.g. by interaction with the existent semiconductors forums (users and suppliers), but not only: Eufanet shall join other international exchange platforms like EDFAS or ANADEF. At the end Eufanet will be much more visible as the European expert network, involved and triggering some of the FA related activities.

Especially the face-to-face exchange is one of the focuses of Eufanet – and shall be more and more fostered: for example the well established workshop within the frame of ESREF or some other thematic discussions meetings, like the Workshop for Optical Localization in Toulouse. These events are not only conference-like meetings with well completed topics, but also include basic or advanced technical stuff as well as case studies and can be the “ignition” for solutions, new ideas – or cooperation.

Also training aspects could be included, in order to provide a systematic and tailored training catalogue for the European FA scene.



Last but not least, such a network can be an important tool for individual communication, primarily but not only for FA topics.